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(71) Applicant (*for all designated States except US*): **CON-**
SIGLIO NAZIONALE DELLE RICERCHE [IT/IT];
Piazzale Aldo Moro, 7, I-00185 Roma (IT).

(72) Inventors; and

(75) Inventors/Applicants (*for US only*): **COCCHI, Massimo**
[IT/IT]; c/o Consiglio Nazionale delle Ricerche, Istituto
per la Sintesi Organica e Fotoreattività, Via P. Gobetti, 101,
I-40129 Bologna (IT). **DI MARCO, Piergiulio** [IT/IT];
c/o Consiglio Nazionale delle Ricerche, Istituto per la
Sintesi Organica e Fotoreattività, Via P. Gobetti, 101,
I-40129 Bologna (IT). **FATTORI, Valeria** [IT/IT]; c/o
Consiglio Nazionale delle Ricerche, Istituto per la Sintesi
Organica e Fotoreattività, Via P. Gobetti, 101, I-40129
Bologna (IT). **GIRO, Gabriele** [IT/IT]; c/o Consiglio
Nazionale delle Ricerche, Istituto per la Sintesi Organica
e Fotoreattività, Via P. Gobetti, 101, I-40129 Bologna (IT).

VIRGILI, Dalia [IT/IT]; c/o Consiglio Nazionale delle
Ricerche, Istituto per la Sintesi Organica e Fotoreattività,
Via P. Gobetti, 101, I-40129 Bologna (IT). **GARULLI,**
Aberto [IT/IT]; c/o Consiglio Nazionale delle Ricerche,
Istituto per la Sintesi Organica e Fotoreattività, Via P.
Gobetti, 101, I-40129 Bologna (IT).

(74) Agents: **JORIO, Paolo** et al.; c/o Studio Torta S.r.l., Via
Viotti, 9, I-10121 Torino (IT).

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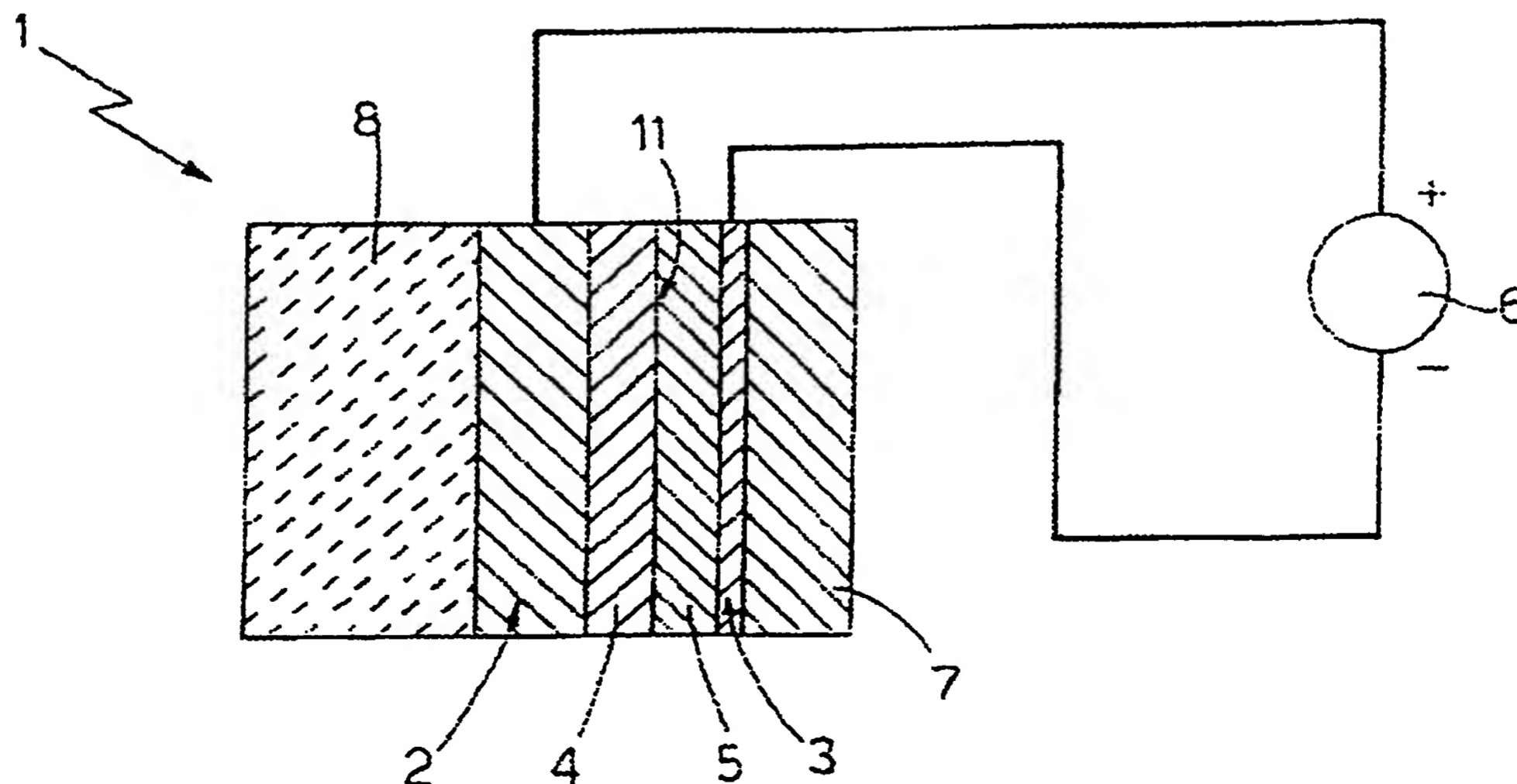
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(54) Title: METHOD FOR REDUCING THE SURFACE ROUGHNESS OF A THIN LAYER OF CONDUCTIVE OXIDES



(57) Abstract: A method for reducing the surface roughness of thin layers of conductive oxides for thin-layer opto-electronic devices envisages polishing with a finishing cloth and an abrasive compound, which has a basic pH and contains silica particles.

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For two-letter codes and other abbreviations, refer to the "Guidance Notes on Codes and Abbreviations" appearing at the beginning of each regular issue of the PCT Gazette.

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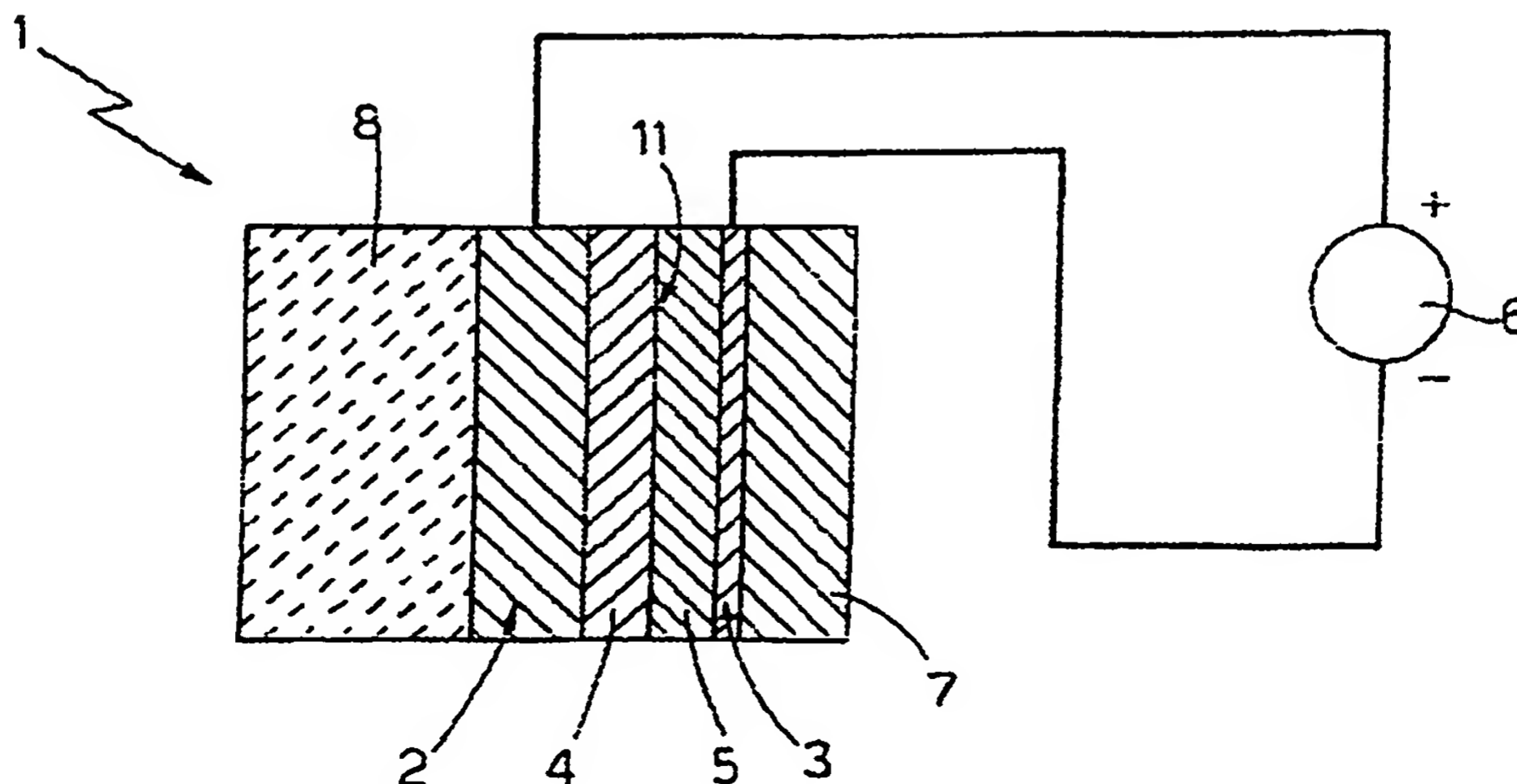
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